

Electrical Characteristics

at $T_{\rm j}$ = 25 °C, unless otherwise specified.

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Static Characteristics					
Drain-source breakdown voltage $V_{\rm GS}$ = 0, $I_{\rm D}$ = 0.25 mA	$V_{(BR)DSS}$	50	_	_	V
Gate threshold voltage $V_{\rm GS}$ = $V_{\rm DS}$, $I_{\rm D}$ = 1.0 mA	$V_{GS(th)}$	1.5	2.0	2.5	
Zero gate voltage drain current $V_{\rm GS}$ = 0 V, $V_{\rm DS}$ = 50 V	$I_{ extsf{DSS}}$				μΑ
$T_{\rm j}$ = 25 °C $T_{\rm j}$ = 125 °C		_	0.1 10	1.0 100	
Gate-source leakage current $V_{\rm GS}$ = 20 V, $V_{\rm DS}$ = 0	I_{GSS}				
$T_{ m j}$ = 25 °C $T_{ m j}$ = 150 °C		- -	10 2	100 4	nA μA
Drain-source on-state resistance $V_{\rm GS}$ = 4.5 V, $I_{\rm D}$ = 7.8 A	$R_{DS(on)}$	_	0.09	0.12	Ω
Dynamic Characteristics					
Forward transconductance $V_{\rm DS} \ge 2 \times I_{\rm D} \times R_{\rm DS(on)max}, I_{\rm D}$ =7.8 A	g_{fs}	5.5	9.5	_	S
Input capacitance $V_{\rm GS}$ = 0, $V_{\rm DS}$ = 25 V, f = 1 MHz	C_{iss}	_	550	735	pF
Output capacitance $V_{\rm GS}$ = 0, $V_{\rm DS}$ = 25 V, f = 1 MHz	$C_{ m oss}$	_	220	320	
Reverse transfer capacitance $V_{\rm GS}$ = 0, $V_{\rm DS}$ = 25 V, f = 1 MHz	C_{rss}	_	85	150	
Turn-on time $t_{\rm on}$, $(t_{\rm on}=t_{\rm d(on)}+t_{\rm r})$ $V_{\rm CC}=30$ V, $V_{\rm GS}=5$ V, $I_{\rm D}=3$ A, $R_{\rm GS}=50$ Ω	t _{d(on)}	_	15	25	ns
Turn-off time t_{off} , $(t_{\text{off}} = t_{\text{d(off)}} + t_{\text{f}})$	t_{r} $t_{d(off)}$	-	70	90	
$V_{\rm CC}$ = 30 V, $V_{\rm GS}$ = 10 V, $I_{\rm D}$ = 3 A, $R_{\rm GS}$ = 50 Ω	$t_{\rm f}$	_	50	70	



Electrical Characteristics (cont'd)

at $T_{\rm j}$ = 25 °C, unless otherwise specified.

Parameter	Symbol		Value	S	Unit
		min.	typ.	max.	
Reverse Diode					
Continuous source current	Is	_	_	15.5	Α
Pulsed source current	I_{SM}	_	_	62	
Diode forward on-voltage $I_{\rm F}$ = 15.5 A, $V_{\rm GS}$ = 0 V	V_{SD}	_	1.3	1.6	V
Reverse recovery time $I_F = I_S$, $di_F/dt = 100 \text{ A/}\mu\text{s}$, $V_R = 30 \text{ V}$	t _{rr}	_	60	_	ns
Reverse recovery charge $I_F = I_S$, $di_F/dt = 100$ A/ μ s, $V_R = 30$ V	Q_{rr}	_	0.10	_	μС
Temperature Sensor			·		
Forward voltage $I_{TS(on)} = 5.0$ mA, $T_j = -55$ + 150 °C Sensor override, $t_p \le 100$ μs	$V_{TS(on)}$		1.3	1.4	V
$T_{\rm j} = -55 \dots + 160 {}^{\circ}{\rm C}$		_	_	10	
Forward current $T_{\rm j} = -55 \dots + 150 ^{\circ}{\rm C}$ Sensor override, $t_{\rm p} \le 100 \mu{\rm s}$	$I_{TS(on)}$	_	_	5	mA
<i>T</i> _j = − 55 + 160 °C		_	_	600	
Holding current, $V_{\rm TS(off)}$ = 5 V, $T_{\rm j}$ = 25 °C $T_{\rm j}$ = 150 °C	I_{H}	0.05 0.05	0.1 0.2	0.5 0.3	
Switching temperature $V_{TS} = 5 \text{ V}$	$T_{TS(on)}$	150	_	_	°C
Turn-off time $V_{TS} = 5 \text{ V}, I_{TS(on)} = 2 \text{ mA}$	$t_{ m off}$	0.5	_	2.5	μs



Examples for short-circuit protection

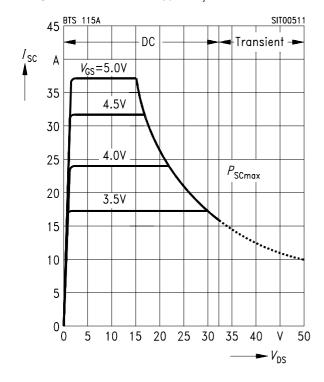
at $T_{\rm j}$ = -55 ... + 150 °C, unless otherwise specified.

Parameter	Symbol	Examples			Unit
		1	2	_	
Drain-source voltage	$V_{ t DS}$	15	30	-	V
Gate-source voltage	V_{GS}	5.0	3.5	_	
Short-circuit current	$I_{ t SC}$	37	17	_	А
Short-circuit dissipation	P_{SC}	550	510	_	W
Response time $T_{\rm j} = 25 ^{\circ}\text{C}$, before short circuit	$t_{SC(off)}$	25	25	_	ms

Short-circuit protection $I_{SC} = f(V_{DS})$

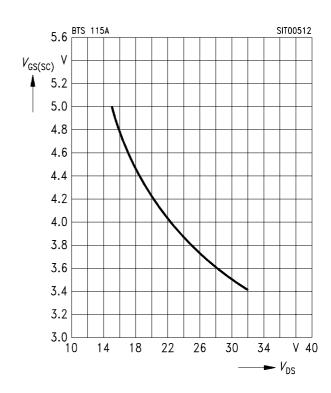
Parameter: V_{GS}

Diagram to determine I_{SC} for $T_j = -55 \dots + 150 \,^{\circ}$ C



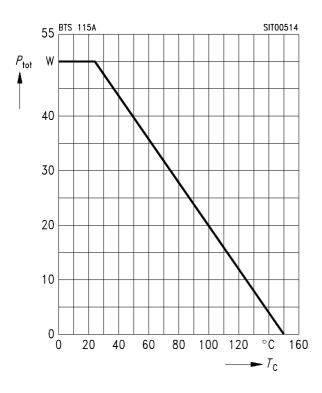
Max. gate voltage $V_{\rm GS(SC)} = f(V_{\rm DS})$

Parameter: $T_j = -55 \dots + 150 \,^{\circ}\text{C}$

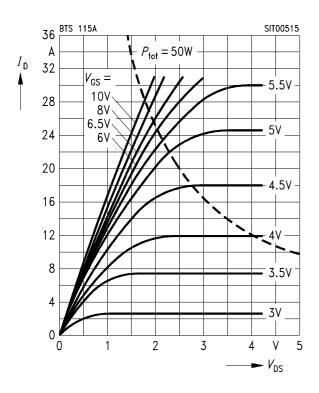




Max. power dissipation $P_{\text{tot}} = f(T_{\text{C}})$

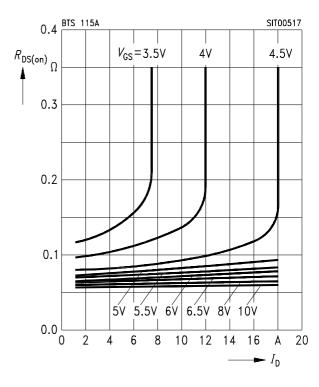


Typical output characteristics $I_{\rm D}$ = f ($V_{\rm DS}$) Parameter: $t_{\rm p}$ = 80 $\mu {\rm s}$

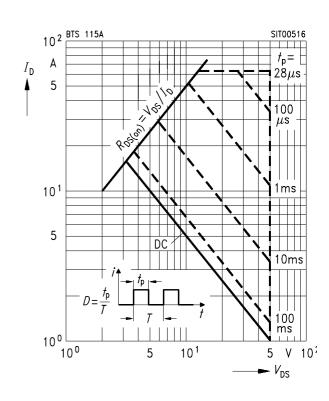


Typ. drain-source on-state resistance

 $R_{\rm DS(on)} = f(I_{\rm D})$ Parameter: $V_{\rm GS}$



Safe operating area $I_D = f(V_{DS})$ Parameter: D = 0.01, $T_C = 25$ °C

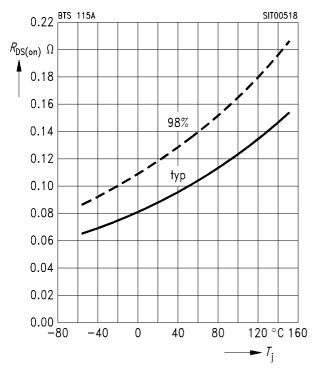




Drain-source on-state resistance

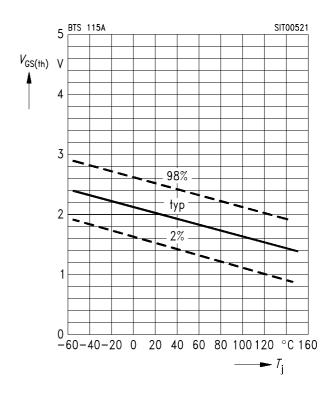
 $R_{\mathrm{DS(on)}} = f(T_{\mathrm{j}})$

Parameter: I_D = 7.8 A, V_{GS} = 4.5 V



Gate threshold voltage $V_{\mathrm{GS(th)}} = f\left(T_{\mathrm{j}}\right)$

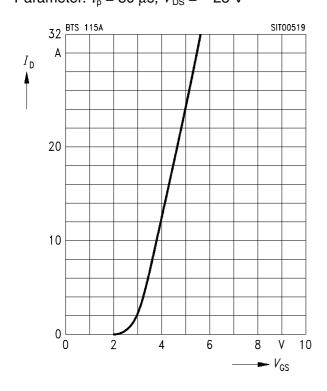
Parameter: $V_{DS} = V_{GS}$, $I_{D} = -1$ mA



Typ. transfer characteristic

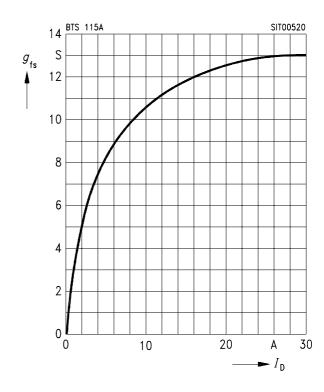
 $I_{\rm D} = f(V_{\rm GS})$

Parameter: $t_p = 80 \mu s$, $V_{DS} = -25 \text{ V}$



Typ. transconductance $g_{fs} = f(I_D)$

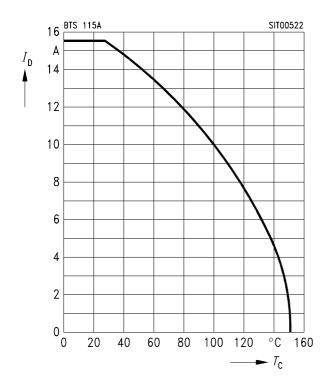
Parameter: t_p = 80 μ s, V_{DS} = -25 V





Continuous drain current $I_D = f(T_C)$

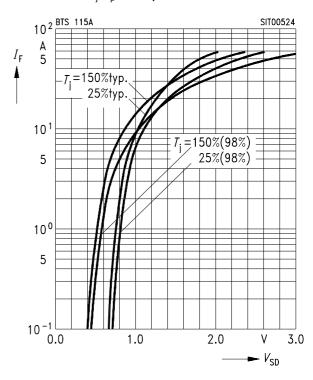
Parameter: $V_{GS} \ge 4.5 \text{ V}$



Forward characteristics of reverse diode

 $I_{\mathsf{F}} = f(V_{\mathsf{SD}})$

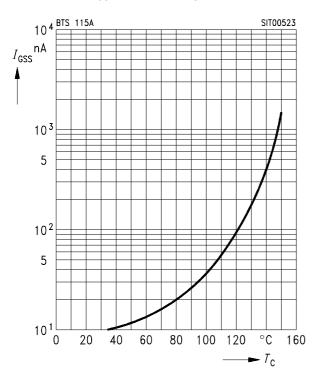
Parameter: $T_{\rm j}$, $t_{\rm p}$ = 80 μ s



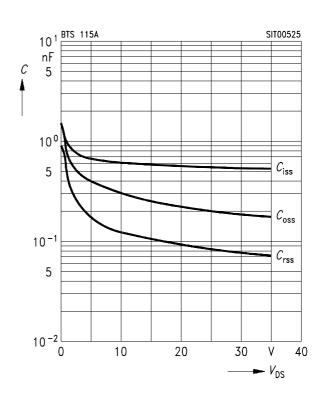
Typ. gate-source leakage current

 $I_{\text{GSS}} = f(T_{\text{C}})$

Parameter: $V_{GS} = -20 \text{ V}$, $V_{DS} = 0$



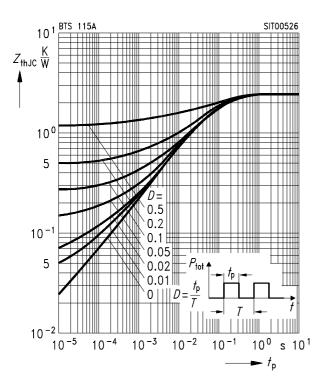
Typ. capacitances $C = f(V_{DS})$ Parameter: $V_{GS} = 0, f = 1 \text{ MHz}$





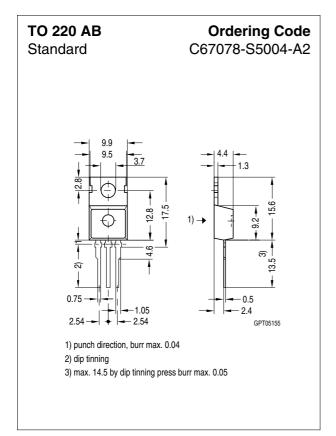
Transient thermal impedance $Z_{\text{thJC}} = f(t_{\text{p}})$

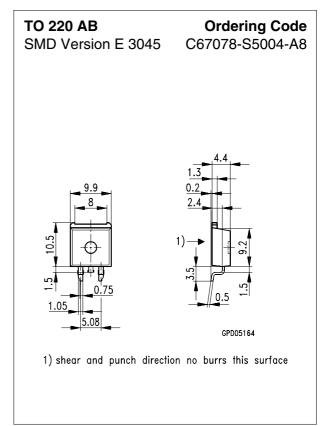
Parameter: $D = t_p/T$











TEMPFET® BTS 115 A



Edition 04.97

Published by Infineon Technologies AG, St.-Martin-Strasse 53, D-81541 München, Germany © Infineon Technologies AG 2000. All Rights Reserved.

Attention please!

The information herein is given to describe certain components and shall not be considered as warranted characteristics.

Terms of delivery and rights to technical change reserved.

We hereby disclaim any and all warranties, including but not limited to warranties of non-infringement, regarding circuits, descriptions and charts stated herein.

Infineon Technologies is an approved CECC manufacturer.

Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies Office in Germany or our Infineon Technologies Representatives worldwide (see address list).

Warnings

Due to technical requirements components may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies Office.

Infineon Technologies Components may only be used in life-support devices or systems with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body, or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.